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The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	8960
Number of Logic Elements/Cells	224000
Total RAM Bits	14248960
Number of I/O	734
Number of Gates	-
Voltage - Supply	0.87V ~ 0.93V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	1517-BBGA, FCBGA
Supplier Device Package	1517-FBGA (40x40)
Purchase URL	https://www.e-xfl.com/product-detail/intel/ep2agz225hf40i4n

Recommended Operating Conditions

This section lists the functional operation limits for AC and DC parameters for Arria II GX and GZ devices. All supplies are required to monotonically reach their full-rail values without plateaus within t_{RAMP}.

Table 1–5 lists the recommended operating conditions for Arria II GX devices.

Table 1–5. Recommended Operating Conditions for Arria II GX Devices *(Note 1)* (Part 1 of 2)

Symbol	Description	Condition	Minimum	Typical	Maximum	Unit
V_{CC}	Supplies power to the core, periphery, I/O registers, PCIe HIP block, and transceiver PCS	—	0.87	0.90	0.93	V
V_{CCCB}	Supplies power to the configuration RAM bits	—	1.425	1.50	1.575	V
V_{CCBAT} *(2)*	Battery back-up power supply for design security volatile key registers	—	1.2	—	3.3	V
V_{CCPD} *(3)*	Supplies power to the I/O pre-drivers, differential input buffers, and MSEL circuitry	—	3.135	3.3	3.465	V
		—	2.85	3.0	3.15	V
		—	2.375	2.5	2.625	V
V_{CCIO}	Supplies power to the I/O banks *(4)*	—	3.135	3.3	3.465	V
		—	2.85	3.0	3.15	V
		—	2.375	2.5	2.625	V
		—	1.71	1.8	1.89	V
		—	1.425	1.5	1.575	V
		—	1.14	1.2	1.26	V
V_{CCD_PLL}	Supplies power to the digital portions of the PLL	—	0.87	0.90	0.93	V
V_{CCA_PLL}	Supplies power to the analog portions of the PLL and device-wide power management circuitry	—	2.375	2.5	2.625	V
V_I	DC Input voltage	—	–0.5	—	3.6	V
V_O	Output voltage	—	0	—	V_{CCIO}	V
V_{CCA}	Supplies power to the transceiver PMA regulator	—	2.375	2.5	2.625	V
V_{CCL_GXB}	Supplies power to the transceiver PMA TX, PMA RX, and clocking	—	1.045	1.1	1.155	V
V_{CCH_GXB}	Supplies power to the transceiver PMA output (TX) buffer	—	1.425	1.5	1.575	V
T_J	Operating junction temperature	Commercial	0	—	85	°C
		Industrial	–40	—	100	°C

Use the following with Equation 1–1:

- R_{SCAL} is the OCT resistance value at power up.
- ΔT is the variation of temperature with respect to the temperature at power up.
- ΔV is the variation of voltage with respect to the V_{CCIO} at power up.
- dR/dT is the percentage change of R_{SCAL} with temperature.
- dR/dV is the percentage change of R_{SCAL} with voltage.

Table 1–14 lists the OCT variation with temperature and voltage after power-up calibration for Arria II GX devices.

Table 1–14. OCT Variation after Power-up Calibration for Arria II GX Devices

Nominal Voltage V_{CCIO} (V)	dR/dT (%/°C)	dR/dV (%/mV)
3.0	0.262	0.035
2.5	0.234	0.039
1.8	0.219	0.086
1.5	0.199	0.136
1.2	0.161	0.288

Table 1–15 lists the OCT variation with temperature and voltage after power-up calibration for Arria II GZ devices.

Table 1–15. OCT Variation after Power-Up Calibration for Arria II GZ Devices *(Note 1)*

Nominal Voltage, V_{CCIO} (V)	dR/dT (%/°C)	dR/dV (%/mV)
3.0	0.189	0.0297
2.5	0.208	0.0344
1.8	0.266	0.0499
1.5	0.273	0.0744
1.2	0.317	0.1241

Note to Table 1–15:

(1) Valid for V_{CCIO} range of ±5% and temperature range of 0° to 85°C.

Pin Capacitance

Table 1–16 lists the pin capacitance for Arria II GX devices.

Table 1–16. Pin Capacitance for Arria II GX Devices

Symbol	Description	Typical	Unit
C_{IO}	Input capacitance on I/O pins, dual-purpose pins (differential I/O, clock, R_{up}, R_{dn}), and dedicated clock input pins	7	pF

Table 1–19 lists the weak pull-up resistor values for Arria II GZ devices.

Table 1–19. Internal Weak Pull-Up Resistor for Arria II GZ Devices *(Note 1)*, *(2)*

Symbol	Description	Conditions	Min	Typ	Max	Unit
R_{PU}	Value of the I/O pin pull-up resistor before and during configuration, as well as user mode if the programmable pull-up resistor option is enabled.	V_{CCIO} = 3.0 V ±5% *(3)*	—	25	—	kΩ
		V_{CCIO} = 2.5 V ±5% *(3)*	—	25	—	kΩ
		V_{CCIO} = 1.8 V ±5% *(3)*	—	25	—	kΩ
		V_{CCIO} = 1.5 V ±5% *(3)*	—	25	—	kΩ
		V_{CCIO} = 1.2 V ±5% *(3)*	—	25	—	kΩ

Notes to Table 1–19:

(1) All I/O pins have an option to enable weak pull-up except configuration, test, and JTAG pins.

(2) The internal weak pull-down feature is only available for the JTAG TCK pin. The typical value for this internal weak pull-down resistor is approximately 25 kΩ .

(3) Pin pull-up resistance values may be lower if an external source drives the pin higher than V_{CCIO}.

Hot Socketing

Table 1–20 lists the hot-socketing specification for Arria II GX and GZ devices.

Table 1–20. Hot Socketing Specifications for Arria II Devices

Symbol	Description	Maximum
$I_{IIOPIN(DC)}$	DC current per I/O pin	300 µA
$I_{IOPIN(AC)}$	AC current per I/O pin	8 mA *(1)*
$I_{XCVRTX(DC)}$	DC current per transceiver TX pin	100 mA
$I_{XCVRRX(DC)}$	DC current per transceiver RX pin	50 mA

Note to Table 1–20:

(1) The I/O ramp rate is 10 ns or more. For ramp rates faster than 10 ns, $|I_{IOPIN}|$ = C dv/dt, in which "C" is I/O pin capacitance and "dv/dt" is slew rate.

Schmitt Trigger Input

The Arria II GX device supports Schmitt trigger input on the TDI, TMS, TCK, nSTATUS, nCONFIG, nCE, CONF_DONE, and DCLK pins. A Schmitt trigger feature introduces hysteresis to the input signal for improved noise immunity, especially for signals with slow edge rates.

Table 1–21 lists the hysteresis specifications across the supported V_{CCIO} range for Schmitt trigger inputs in Arria II GX devices.

Table 1–21. Schmitt Trigger Input Hysteresis Specifications for Arria II GX Devices

Symbol	Description	Condition (V)	Minimum	Unit
$V_{Schmitt}$	Hysteresis for Schmitt trigger input	V_{CCIO} = 3.3	220	mV
		V_{CCIO} = 2.5	180	mV
		V_{CCIO} = 1.8	110	mV
		V_{CCIO} = 1.5	70	mV

Table 1–23. Single-Ended I/O Standards for Arria II GZ Devices (Part 2 of 2)

I/O Standard	V_{CCIO} (V)			V_{IL} (V)		V_{IH} (V)		V_{OL} (V)	V_{OH} (V)	I_{OL} (mA)	I_{OH} (mA)
	Min	Typ	Max	Min	Max	Min	Max	Max	Min		
1.2 V	1.14	1.2	1.26	-0.3	0.35 × V_{CCIO}	0.65 × V_{CCIO}	V_{CCIO} + 0.3	0.25 × V_{CCIO}	0.75 × V_{CCIO}	2	-2
3.0-V PCI	2.85	3	3.15	—	0.3 × V_{CCIO}	0.5 × V_{CCIO}	3.6	0.1 × V_{CCIO}	0.9 × V_{CCIO}	1.5	-0.5
3.0-V PCI-X	2.85	3	3.15	—	0.35 × V_{CCIO}	0.5 × V_{CCIO}	—	0.1 × V_{CCIO}	0.9 × V_{CCIO}	1.5	-0.5

Table 1–24 lists the single-ended SSTL and HSTL I/O reference voltage specifications for Arria II GX devices.

Table 1–24. Single-Ended SSTL and HSTL I/O Reference Voltage Specifications for Arria II GX Devices

I/O Standard	V_{CCIO} (V)			V_{REF} (V)			V_{TT} (V)		
	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max
SSTL-2 Class I, II	2.375	2.5	2.625	0.49 × V_{CCIO}	0.5 × V_{CCIO}	0.51 × V_{CCIO}	V_{REF} - 0.04	V_{REF}	V_{REF} + 0.04
SSTL-18 Class I, II	1.71	1.8	1.89	0.833	0.9	0.969	V_{REF} - 0.04	V_{REF}	V_{REF} + 0.04
SSTL-15 Class I, II	1.425	1.5	1.575	0.47 × V_{CCIO}	0.5 × V_{CCIO}	0.53 × V_{CCIO}	0.47 × V_{CCIO}	0.5 × V_{CCIO}	0.53 × V_{CCIO}
HSTL-18 Class I, II	1.71	1.8	1.89	0.85	0.9	0.95	0.85	0.9	0.95
HSTL-15 Class I, II	1.425	1.5	1.575	0.71	0.75	0.79	0.71	0.75	0.79
HSTL-12 Class I, II	1.14	1.2	1.26	0.48 × V_{CCIO}	0.5 × V_{CCIO}	0.52 × V_{CCIO}	—	V_{CCIO}/2	—

Table 1–25 lists the single-ended SSTL and HSTL I/O reference voltage specifications for Arria II GZ devices.

Table 1–25. Single-Ended SSTL and HSTL I/O Reference Voltage Specifications for Arria II GZ Devices

I/O Standard	V_{CCIO} (V)			V_{REF} (V)			V_{TT} (V)		
	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max
SSTL-2 Class I, II	2.375	2.5	2.625	0.49 × V_{CCIO}	0.5 × V_{CCIO}	0.51 × V_{CCIO}	V_{REF} - 0.04	V_{REF}	V_{REF} + 0.04
SSTL-18 Class I, II	1.71	1.8	1.89	0.833	0.9	0.969	V_{REF} - 0.04	V_{REF}	V_{REF} + 0.04
SSTL-15 Class I, II	1.425	1.5	1.575	0.47 × V_{CCIO}	0.5 × V_{CCIO}	0.53 × V_{CCIO}	0.47 × V_{CCIO}	V_{REF}	0.53 × V_{CCIO}
HSTL-18 Class I, II	1.71	1.8	1.89	0.85	0.9	0.95	—	V_{CCIO}/2	—
HSTL-15 Class I, II	1.425	1.5	1.575	0.68	0.75	0.9	—	V_{CCIO}/2	—
HSTL-12 Class I, II	1.14	1.2	1.26	0.47 × V_{CCIO}	0.5 × V_{CCIO}	0.53 × V_{CCIO}	—	V_{CCIO}/2	—

Table 1–27. Single-Ended SSTL and HSTL I/O Standards Signal Specifications for Arria II GZ Devices (Part 2 of 2)

I/O Standard	$V_{IL(DC)}$ (V)		$V_{IH(DC)}$ (V)		$V_{IL(AC)}$ (V)	$V_{IH(AC)}$ (V)	V_{OL} (V)	V_{OH} (V)	I_{OL} (mA)	I_{OH} (mA)
	Min	Max	Min	Max	Max	Min	Max	Min		
SSTL-15 Class II	—	V_{REF} - 0.1	V_{REF} + 0.1	—	V_{REF} - 0.175	V_{REF} + 0.175	0.2 × V_{CCIO}	0.8 × V_{CCIO}	16	-16
HSTL-18 Class I	—	V_{REF} - 0.1	V_{REF} + 0.1	—	V_{REF} - 0.2	V_{REF} + 0.2	0.4	V_{CCIO} - 0.4	8	-8
HSTL-18 Class II	—	V_{REF} - 0.1	V_{REF} + 0.1	—	V_{REF} - 0.2	V_{REF} + 0.2	0.4	V_{CCIO} - 0.4	16	-16
HSTL-15 Class I	—	V_{REF} - 0.1	V_{REF} + 0.1	—	V_{REF} - 0.2	V_{REF} + 0.2	0.4	V_{CCIO} - 0.4	8	-8
HSTL-15 Class II	—	V_{REF} - 0.1	V_{REF} + 0.1	—	V_{REF} - 0.2	V_{REF} + 0.2	0.4	V_{CCIO} - 0.4	16	-16
HSTL-12 Class I	-0.15	V_{REF} - 0.08	V_{REF} + 0.08	V_{CCIO} + 0.15	V_{REF} - 0.15	V_{REF} + 0.15	0.25× V_{CCIO}	0.75× V_{CCIO}	8	-8
HSTL-12 Class II	-0.15	V_{REF} - 0.08	V_{REF} + 0.08	V_{CCIO} + 0.15	V_{REF} - 0.15	V_{REF} + 0.15	0.25× V_{CCIO}	0.75 × V_{CCIO}	16	-16

Table 1–28 lists the differential SSTL I/O standards for Arria II GX devices.

Table 1–28. Differential SSTL I/O Standards for Arria II GX Devices

I/O Standard	V_{CCIO} (V)			$V_{SWING(DC)}$ (V)		$V_{X(AC)}$ (V)			$V_{SWING(AC)}$ (V)		$V_{OX(AC)}$ (V)		
	Min	Typ	Max	Min	Max	Min	Typ	Max	Min	Max	Min	Typ	Max
SSTL-2 Class I, II	2.375	2.5	2.625	0.36	V_{CCIO}	$V_{CCIO}/2$ - 0.2	—	$V_{CCIO}/2$ + 0.2	0.7	V_{CCIO}	$V_{CCIO}/2$ - 0.15	—	$V_{CCIO}/2$ + 0.15
SSTL-18 Class I, II	1.71	1.8	1.89	0.25	V_{CCIO}	$V_{CCIO}/2$ - 0.175	—	$V_{CCIO}/2$ + 0.175	0.5	V_{CCIO}	$V_{CCIO}/2$ - 0.125	—	$V_{CCIO}/2$ + 0.125
SSTL-15 Class I, II	1.425	1.5	1.575	0.2	—	—	$V_{CCIO}/2$	—	0.35	—	—	$V_{CCIO}/2$	—

Table 1–29 lists the differential SSTL I/O standards for Arria II GZ devices

Table 1–29. Differential SSTL I/O Standards for Arria II GZ Devices

I/O Standard	V_{CCIO} (V)			$V_{SWING(DC)}$ (V)		$V_{X(AC)}$ (V)			$V_{SWING(AC)}$ (V)		$V_{OX(AC)}$ (V)		
	Min	Typ	Max	Min	Max	Min	Typ	Max	Min	Max	Min	Typ	Max
SSTL-2 Class I, II	2.375	2.5	2.625	0.3	V_{CCIO} + 0.6	$V_{CCIO}/2$ - 0.2	—	$V_{CCIO}/2$ + 0.2	0.62	V_{CCIO} + 0.6	$V_{CCIO}/2$ - 0.15	—	$V_{CCIO}/2$ + 0.15
SSTL-18 Class I, II	1.71	1.8	1.89	0.25	V_{CCIO} + 0.6	$V_{CCIO}/2$ - 0.175	—	$V_{CCIO}/2$ + 0.175	0.5	V_{CCIO} + 0.6	$V_{CCIO}/2$ - 0.125	—	$V_{CCIO}/2$ + 0.125
SSTL-15 Class I, II	1.425	1.5	1.575	0.2	—	—	$V_{CCIO}/2$	—	0.35	—	—	$V_{CCIO}/2$	—

Table 1–30 lists the HSTL I/O standards for Arria II GX devices.

Table 1–30. Differential HSTL I/O Standards for Arria II GX Devices

I/O Standard	V_{CCIO} (V)			$V_{DIF(DC)}$ (V)		$V_{X(AC)}$ (V)			$V_{CM(DC)}$ (V)			$V_{DIF(AC)}$ (V)	
	Min	Typ	Max	Min	Max	Min	Typ	Max	Min	Typ	Max	Min	Max
HSTL-18 Class I	1.71	1.8	1.89	0.2	—	0.85	—	0.95	0.88	—	0.95	0.4	—
HSTL-15 Class I, II	1.425	1.5	1.575	0.2	—	0.71	—	0.79	0.71	—	0.79	0.4	—
HSTL-12 Class I, II	1.14	1.2	1.26	0.16	—	—	0.5 × V_{CCIO}	—	0.48 × V_{CCIO}	0.5 × V_{CCIO}	0.52 × V_{CCIO}	0.3	—

Table 1–31 lists the HSTL I/O standards for Arria II GZ devices.

Table 1–31. Differential HSTL I/O Standards for Arria II GZ Devices

I/O Standard	V_{CCIO} (V)			$V_{DIF(DC)}$ (V)		$V_{X(AC)}$ (V)			$V_{CM(DC)}$ (V)			$V_{DIF(AC)}$ (V)	
	Min	Typ	Max	Min	Max	Min	Typ	Max	Min	Typ	Max	Min	Max
HSTL-18 Class I	1.71	1.8	1.89	0.2	—	0.78	—	1.12	0.78	—	1.12	0.4	—
HSTL-15 Class I, II	1.425	1.5	1.575	0.2	—	0.68	—	0.9	0.68	—	0.9	0.4	—
HSTL-12 Class I, II	1.14	1.2	1.26	0.16	V_{CCIO} + 0.3	—	0.5 × V_{CCIO}	—	0.4 × V_{CCIO}	0.5 × V_{CCIO}	0.6 × V_{CCIO}	0.3	V_{CCIO} + 0.48

Table 1–32 lists the differential I/O standard specifications for Arria II GX devices.

Table 1–32. Differential I/O Standard Specifications for Arria II GX Devices *(Note 1)*

I/O Standard	V_{CCIO} (V)			V_{ID} (mV)			V_{ICM} (V) *(2)*		V_{OD} (V) *(3)*			V_{OCM} (V)		
	Min	Typ	Max	Min	Cond.	Max	Min	Max	Min	Typ	Max	Min	Typ	Max
2.5 V LVDS	2.375	2.5	2.625	100	V_{CM} = 1.25 V	—	0.05	1.80	0.247	—	0.6	1.125	1.25	1.375
RSDS *(4)*	2.375	2.5	2.625	—	—	—	—	—	0.1	0.2	0.6	0.5	1.2	1.4
Mini-LVDS *(4)*	2.375	2.5	2.625	—	—	—	—	—	0.25	—	0.6	1	1.2	1.4
LVPECL *(5)*	2.375	2.5	2.625	300	—	—	0.6	1.8	—	—	—	—	—	—
BLVDS *(6)*	2.375	2.5	2.625	100	—	—	—	—	—	—	—	—	—	—

Notes to Table 1–32:

(1) The 1.5 V PCML transceiver I/O standard specifications are described in "Transceiver Performance Specifications" on page 1–21.
(2) V_{IN} range: 0 <= V_{IN} <= 1.85 V.
(3) R_L range: 90 <= RL <= 110 Ω.
(4) The RSDS and mini-LVDS I/O standards are only supported for differential outputs.
(5) The LVPECL input standard is supported at the dedicated clock input pins (GCLK) only.
(6) There are no fixed V_{ICM}, V_{OD}, and V_{OCM} specifications for BLVDS. These specifications depend on the system topology.

Switching Characteristics

This section provides performance characteristics of the Arria II GX and GZ core and periphery blocks for commercial grade devices. The following tables are considered final and are based on actual silicon characterization and testing. These numbers reflect the actual performance of the device under worst-case silicon process, voltage, and junction temperature conditions.

Transceiver Performance Specifications

Table 1–34 lists the Arria II GX transceiver specifications.

Table 1–34. Transceiver Specifications for Arria II GX Devices *(Note 1)* (Part 1 of 7)

Symbol/ Description	Condition	I3			C4			C5 and I5			C6			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
Reference Clock														
Supported I/O Standards	1.2-V PCML, 1.5-V PCML, 2.5-V PCML, Differential LVPECL, LVDS, and HCSL													
Input frequency from REFCLK input pins	—	50	—	622.08	50	—	622.08	50	—	622.08	50	—	622.08	MHz
Input frequency from PLD input	—	50	—	200	50	—	200	50	—	200	50	—	200	MHz
Absolute V_{MAX} for a REFCLK pin	—	—	—	2.2	—	—	2.2	—	—	2.2	—	—	2.2	V
Absolute V_{MIN} for a REFCLK pin	—	–0.3	—	—	–0.3	—	—	–0.3	—	—	–0.3	—	—	V
Rise/fall time *(2)*	—	—	—	0.2	—	—	0.2	—	—	0.2	—	—	0.2	UI
Duty cycle	—	45	—	55	45	—	55	45	—	55	45	—	55	%
Peak-to-peak differential input voltage	—	200	—	2000	200	—	2000	200	—	2000	200	—	2000	mV
Spread-spectrum modulating clock frequency	PCIe	30	—	33	30	—	33	30	—	33	30	—	33	kHz

Table 1–34. Transceiver Specifications for Arria II GX Devices *(Note 1)* (Part 5 of 7)

Symbol/ Description	Condition	I3			C4			C5 and I5			C6			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
LTD lock time *(11)*	—	0	100	4000	0	100	4000	0	100	4000	0	100	4000	ns
Data lock time from `rx_freqlocked` *(12)*	—	—	—	4000	—	—	4000	—	—	4000	—	—	4000	ns
Programmable DC gain	DC Gain Setting = 0	—	0	—	—	0	—	—	0	—	—	0	—	dB
	DC Gain Setting = 1	—	3	—	—	3	—	—	3	—	—	3	—	dB
	DC Gain Setting = 2	—	6	—	—	6	—	—	6	—	—	6	—	dB
Transmitter														
Supported I/O Standards	1.5-V PCML													
Data rate	—	600	—	6375	600	—	3750	600	—	3750	600	—	3125	Mbps
V_{OCM}	0.65 V setting	—	650	—	—	650	—	—	650	—	—	650	—	mV
Differential on-chip termination resistors	100–Ω setting	—	100	—	—	100	—	—	100	—	—	100	—	Ω
Return loss differential mode	PCIe	50 MHz to 1.25 GHz: –10dB												
	XAUI	312 MHz to 625 MHz: –10dB 625 MHz to 3.125 GHz: –10dB/decade slope												
Return loss common mode	PCIe	50 MHz to 1.25 GHz: –6dB												
Rise time *(2)*	—	50	—	200	50	—	200	50	—	200	50	—	200	ps
Fall time	—	50	—	200	50	—	200	50	—	200	50	—	200	ps

Table 1–34. Transceiver Specifications for Arria II GX Devices *(Note 1)* (Part 7 of 7)

Symbol/ Description	Condition	I3			C4			C5 and I5			C6			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
Digital reset pulse width	—	Minimum is 2 parallel clock cycles												

Notes to Table 1–34:

(1) For AC-coupled links, the on-chip biasing circuit is switched off before and during configuration. Ensure that input specifications are not violated during this period.

(2) The rise/fall time is specified from 20% to 80%.

(3) To calculate the REFCLK rms phase jitter requirement at reference clock frequencies other than 100 MHz, use the following formula:
REFCLK rms phase jitter at f (MHz) = REFCLK rms phase jitter at 100 MHz * 100/f.

(4) The minimum `reconfig_clk` frequency is 2.5 MHz if the transceiver channel is configured in **Transmitter only** mode. The minimum `reconfig_clk` frequency is 37.5 MHz if the transceiver channel is configured in **Receiver only** or **Receiver and Transmitter** mode. For more information, refer to *AN 558: Implementing Dynamic Reconfiguration in Arria II Devices*.

(5) If your design uses more than one dynamic reconfiguration controller instances (`altgx_reconfig`) to control the transceiver channels (`altgx`) physically located on the same side of the device, and if you use different `reconfig_clk` sources for these `altgx_reconfig` instances, the delta time between any two of these `reconfig_clk` sources becoming stable must not exceed the maximum specification listed.

(6) The device cannot tolerate prolonged operation at this absolute maximum.

(7) You must use the 1.1-V RX V_{ICM} setting if the input serial data standard is LVDS and the link is DC-coupled.

(8) The rate matcher supports only up to ±300 parts per million (ppm).

(9) Time taken to `rx_pll_locked` goes high from `rx_analogreset` de-assertion. Refer to Figure 1–1.

(10) The time in which the CDR must be kept in lock-to-reference mode after `rx_pll_locked` goes high and before `rx_locktodata` is asserted in manual mode. Refer to Figure 1–1.

(11) The time taken to recover valid data after the `rx_locktodata` signal is asserted in manual mode. Refer to Figure 1–1.

(12) The time taken to recover valid data after the `rx_freqlocked` signal goes high in automatic mode. Refer to Figure 1–2.

(13) To support data rates lower than the minimum specification through oversampling, use the CDR in LTR mode only.

Table 1–35. Transceiver Specifications for Arria II GZ Devices (Part 4 of 5)

Symbol/ Description	Conditions	–C3 and –I3 *(1)*			–C4 and –I4			Unit
		Min	Typ	Max	Min	Typ	Max	
Transmitter								
Supported I/O Standards	1.5-V PCML							
Data rate *(14)*	—	600	—	6375	600	—	3750	Mbps
V_{OCM}	0.65 V setting	—	650	—	—	650	—	mV
Differential on-chip termination resistors	85–Ω setting	85 ± 15%			85 ± 15%			Ω
	100–Ω setting	100 ± 15%			100 ± 15%			Ω
	120–Ω setting	120 ± 15%			120 ± 15%			Ω
	150-Ω setting	150 ± 15%			150 ± 15%			Ω
Differential and common mode return loss	PCIe Gen1 and Gen2 (TX V_{OD}=4), XAUI (TX V_{OD}=6), HiGig+ (TX V_{OD}=6), CEI SR/LR (TX V_{OD}=8), SRIO SR (V_{OD}=6), SRIO LR (V_{OD}=8), CPRI LV (V_{OD}=6), CPRI HV (V_{OD}=2), OBSAI (V_{OD}=6), SATA (V_{OD}=4),	Compliant						—
Rise time *(15)*	—	50	—	200	50	—	200	ps
Fall time *(15)*	—	50	—	200	50	—	200	ps
Intra-differential pair skew	—	—	—	15	—	—	15	ps
Intra-transceiver block transmitter channel-to-channel skew	×4 PMA and PCS bonded mode Example: XAUI, PCIe ×4, Basic ×4	—	—	120	—	—	120	ps
Inter-transceiver block transmitter channel-to-channel skew	×8 PMA and PCS bonded mode Example: PCIe ×8, Basic ×8	—	—	500	—	—	500	ps
CMU0 PLL and CMU1 PLL								
Supported Data Range	—	600	—	6375	600	—	3750	Mbps
`pll_powerdown` minimum pulse width (`tpll_powerdown`)	—	1			1			µs
CMU PLL lock time from `pll_powerdown` de-assertion	—	—	—	100	—	—	100	µs

Figure 1–3 shows the differential receiver input waveform.

Figure 1–3. Receiver Input Waveform

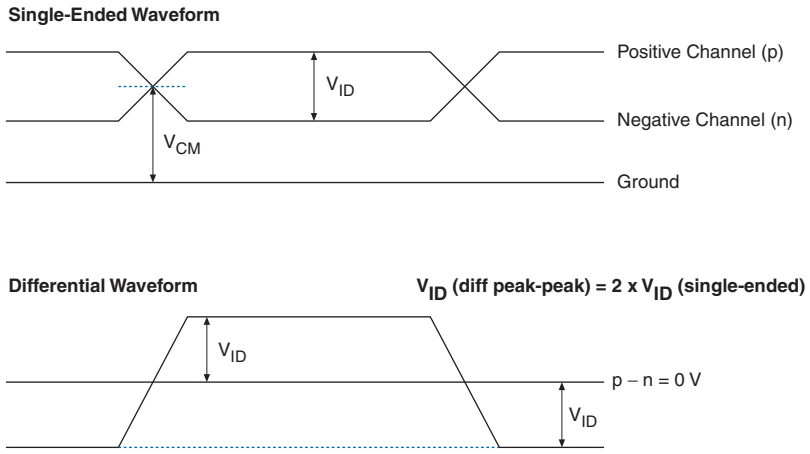


Figure 1–4 shows the transmitter output waveform.

Figure 1–4. Transmitter Output Waveform

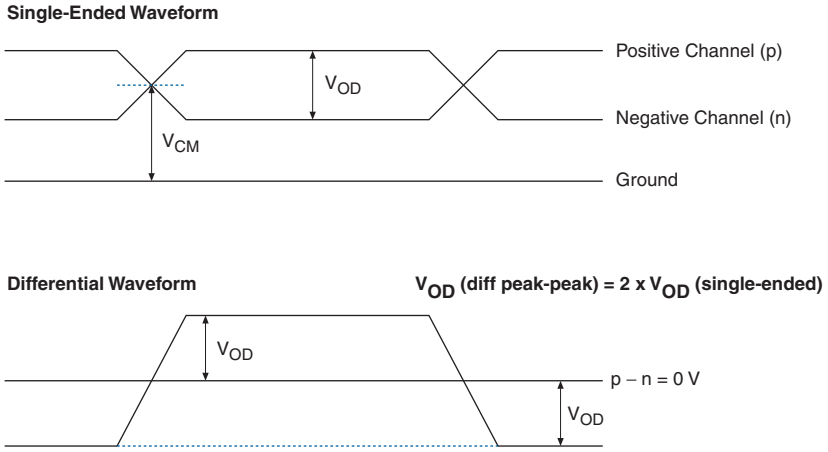


Table 1–36 lists the typical V_{OD} for TX term that equals 85 Ω for Arria II GZ devices.

Table 1–36. Typical V_{OD} Setting, TX Term = 85 Ω for Arria II GZ Devices

Symbol	V_{OD} Setting (mV)							
	0	1	2	3	4	5	6	7
V_{OD} differential peak-to-peak Typical (mV)	170 ± 20%	340 ± 20%	510 ± 20%	595 ± 20%	680 ± 20%	765 ± 20%	850 ± 20%	1020 ± 20%

Table 1–40. Transceiver Block Jitter Specifications for Arria II GX Devices *(Note 1)* (Part 8 of 10)

Symbol/ Description	Conditions	I3			C4			C5, I5			C6			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
CPRI Transmit Jitter Generation *(11)*														
Total jitter	E.6.HV, E.12.HV Pattern = CJPAT	—	—	0.279	—	—	0.279	—	—	0.279	—	—	0.279	UI
	E.6.LV, E.12.LV, E.24.LV, E.30.LV Pattern = CJTPAT	—	—	0.35	—	—	0.35	—	—	0.35	—	—	0.35	UI
Deterministic jitter	E.6.HV, E.12.HV Pattern = CJPAT	—	—	0.14	—	—	0.14	—	—	0.14	—	—	0.14	UI
	E.6.LV, E.12.LV, E.24.LV, E.30.LV Pattern = CJTPAT	—	—	0.17	—	—	0.17	—	—	0.17	—	—	0.17	UI
CPRI Receiver Jitter Tolerance *(11)*														
Total jitter tolerance	E.6.HV, E.12.HV Pattern = CJPAT	> 0.66			> 0.66			> 0.66			> 0.66			UI
Deterministic jitter tolerance	E.6.HV, E.12.HV Pattern = CJPAT	> 0.4			> 0.4			> 0.4			> 0.4			UI
Total jitter tolerance	E.6.LV, E.12.LV, E.24.LV, E.30.LV Pattern = CJTPAT	> 0.65			> 0.65			> 0.65			> 0.65			UI
	E.60.LV Pattern = PRBS31	> 0.6			—			—			—			UI
Deterministic jitter tolerance	E.6.LV, E.12.LV, E.24.LV, E.30.LV Pattern = CJTPAT	> 0.37			> 0.37			> 0.37			> 0.37			UI
	E.60.LV Pattern = PRBS31	> 0.45			—			—			—			UI
Combined deterministic and random jitter tolerance	E.6.LV, E.12.LV, E.24.LV, E.30.LV Pattern = CJTPAT	> 0.55			> 0.55			> 0.55			> 0.55			UI
OBSAI Transmit Jitter Generation *(12)*														
Total jitter at 768 Mbps, 1536 Mbps, and 3072 Mbps	REFCLK = 153.6 MHz Pattern = CJPAT	—	—	0.35	—	—	0.35	—	—	0.35	—	—	0.35	UI
Deterministic jitter at 768 Mbps, 1536 Mbps, and 3072 Mbps	REFCLK = 153.6 MHz Pattern = CJPAT	—	—	0.17	—	—	0.17	—	—	0.17	—	—	0.17	UI

Table 1–40. Transceiver Block Jitter Specifications for Arria II GX Devices *(Note 1)* (Part 9 of 10)

Symbol/ Description	Conditions	I3			C4			C5, I5			C6			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
OBSAI Receiver Jitter Tolerance *(12)*														
Deterministic jitter tolerance at 768 Mbps, 1536 Mbps, and 3072 Mbps	Pattern = CJPAT	> 0.37			> 0.37			> 0.37			> 0.37			UI
Combined deterministic and random jitter tolerance at 768 Mbps, 1536 Mbps, and 3072 Mbps	Pattern = CJPAT	> 0.55			> 0.55			> 0.55			> 0.55			UI
Sinusoidal jitter tolerance at 768 Mbps	Jitter frequency = 5.4 KHz Pattern = CJPAT	> 8.5			> 8.5			> 8.5			> 8.5			UI
	Jitter frequency = 460.8 KHz to 20 MHz Pattern = CJPAT	> 0.1			> 0.1			> 0.1			> 0.1			UI
Sinusoidal jitter tolerance at 1536 Mbps	Jitter frequency = 10.9 KHz Pattern = CJPAT	> 8.5			> 8.5			> 8.5			> 8.5			UI
	Jitter frequency = 921.6 KHz to 20 MHz Pattern = CJPAT	> 0.1			> 0.1			> 0.1			> 0.1			UI

Table 1–41. Transceiver Block Jitter Specifications for Arria II GZ Devices *(Note 1)*, *(2)* (Part 7 of 7)

Symbol/ Description	Conditions	–C3 and –I3			–C4 and –I4			Unit
		Min	Typ	Max	Min	Typ	Max	
OBSAI Receiver Jitter Tolerance *(15)*								
Deterministic jitter tolerance at 768 Mbps, 1536 Mbps, and 3072 Mbps	Pattern = CJPAT		> 0.37			> 0.37		UI
Combined deterministic and random jitter tolerance at 768 Mbps, 1536 Mbps, and 3072 Mbps	Pattern = CJPAT		> 0.55			> 0.55		UI
Sinusoidal jitter tolerance at 768 Mbps	Jitter frequency = 5.4 KHz Pattern = CJPAT		> 8.5			> 8.5		UI
	Jitter frequency = 460 MHz to 20 MHz Pattern = CJPAT		> 0.1			> 0.1		UI
Sinusoidal jitter tolerance at 1536 Mbps	Jitter frequency = 10.9 KHz Pattern = CJPAT		> 8.5			> 8.5		UI
	Jitter frequency = 921.6 MHz to 20 MHz Pattern = CJPAT		> 0.1			> 0.1		UI
Sinusoidal jitter tolerance at 3072 Mbps	Jitter frequency = 21.8 KHz Pattern = CJPAT		> 8.5			> 8.5		UI
	Jitter frequency = 1843.2 MHz to 20 MHz Pattern = CJPAT		> 0.1			> 0.1		UI

Notes to Table 1–41:

(1) Dedicated `refclk` pins were used to drive the input reference clocks.
(2) The jitter numbers are valid for the stated conditions only.
(3) The jitter numbers for SONET/SDH are compliant to the GR-253-CORE Issue 3 Specification.
(4) The jitter numbers for Fibre Channel are compliant to the FC-PI-4 Specification revision 6.10.
(5) The Fibre Channel transmitter jitter generation numbers are compliant to the specification at the δ_T inter operability point.
(6) The Fibre Channel receiver jitter tolerance numbers are compliant to the specification at the δ_R interpretability point.
(7) The jitter numbers for XAUI are compliant to the IEEE802.3ae-2002 Specification.
(8) The jitter numbers for PCIe are compliant to the PCIe Base Specification 2.0.
(9) Arria II GZ PCIe receivers are compliant to this specification provided the $V_{TX-CM-DC-ACTIVEIDLE-DELTA}$ of the upstream transmitter is less than 50 mV.
(10) The jitter numbers for SRIO are compliant to the RapidIO Specification 1.3.
(11) The jitter numbers for GIGE are compliant to the IEEE802.3-2002 Specification.
(12) The HD-SDI and 3G-SDI jitter numbers are compliant to the SMPTE292M and SMPTE424M Specifications.
(13) The jitter numbers for Serial Attached SCSI (SAS) are compliant to the SAS-2.1 Specification.
(14) The jitter numbers for CPRI are compliant to the CPRI Specification V3.0.
(15) The jitter numbers for OBSAI are compliant to the OBSAI RP3 Specification V4.1.

Periphery Performance

This section describes periphery performance, including high-speed I/O, external memory interface, and IOE programmable delay.

I/O performance supports several system interfaces, for example the high-speed I/O interface, external memory interface, and the PCI/PCI-X bus interface. I/O using SSTL-18 Class I termination standard can achieve up to the stated DDR2 SDRAM interfacing speed with typical DDR2 SDRAM memory interface setup. I/O using general purpose I/O (GPIO) standards such as 3.0, 2.5, 1.8, or 1.5 LVTTL/LVCMOS are capable of typical 200 MHz interfacing frequency with 10pF load.

☞ Actual achievable frequency depends on design- and system-specific factors. You should perform HSPICE/IBIS simulations based on your specific design and system setup to determine the maximum achievable frequency in your system.

High-Speed I/O Specification

Table 1–53 lists the high-speed I/O timing for Arria II GX devices.

Table 1–53. High-Speed I/O Specifications for Arria II GX Devices (Part 1 of 4)

Symbol	Conditions	I3		C4		C5,I5		C6		Unit
		Min	Max	Min	Max	Min	Max	Min	Max	
Clock										
f_{HSCLK_IN} (input clock frequency)–Row I/O	Clock boost factor, W = 1 to 40 *(1)*	5	670	5	670	5	622	5	500	MHz
f_{HSCLK_IN} (input clock frequency)–Column I/O	Clock boost factor, W = 1 to 40 *(1)*	5	500	5	500	5	472.5	5	472.5	MHz
f_{HSCLK_OUT} (output clock frequency)–Row I/O	—	5	670	5	670	5	622	5	500	MHz
f_{HSCLK_OUT} (output clock frequency)–Column I/O	—	5	500	5	500	5	472.5	5	472.5	MHz

Table 1–55. DPA Lock Time Specifications for Arria II Devices *(Note 1)*, *(2)*, *(3)*

Standard	Training Pattern	Number of Data Transitions in One Repetition of the Training Pattern	Number of Repetitions per 256 Data Transitions *(4)*	Maximum
SPI-4	00000000001111111111	2	128	640 data transitions
Parallel Rapid I/O	00001111	2	128	640 data transitions
	10010000	4	64	640 data transitions
Miscellaneous	10101010	8	32	640 data transitions
	01010101	8	32	640 data transitions

Notes to Table 1–55:

(1) The DPA lock time is for one channel.
(2) One data transition is defined as a 0-to-1 or 1-to-0 transition.
(3) The DPA lock time stated in the table applies to both commercial and industrial grade.
(4) This is the number of repetitions for the stated training pattern to achieve the 256 data transitions.

Figure 1–5 shows the LVDS soft-CDR/DPA sinusoidal jitter tolerance specification for Arria II GZ devices at a data rate less than 1.25 Gbps and all the Arria II GX devices.

Figure 1–5. LVDS Soft-CDR/DPA Sinusoidal Jitter Tolerance Specification for All Arria II GX Devices and for Arria II GZ Devices at a Data Rate less than 1.25 Gbps

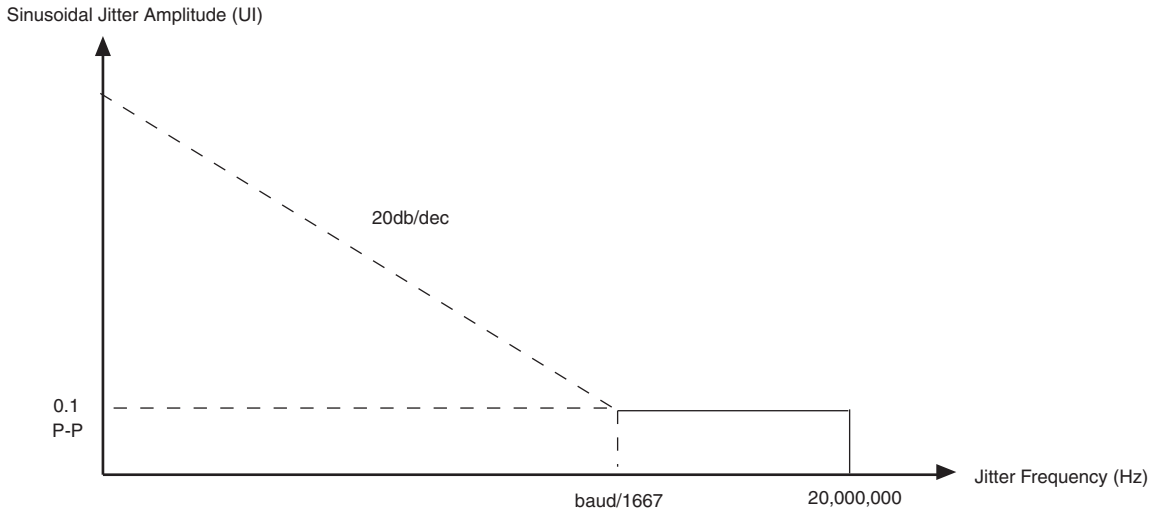


Figure 1–6 shows the LVDS soft-CDR/DPA sinusoidal jitter tolerance specification for Arria II GZ devices at 1.25 Gbps data rate.

Figure 1–6. LVDS Soft-CDR/DPA Sinusoidal Jitter Tolerance Specification for Arria II GZ Devices at a 1.25 Gbps Data Rate

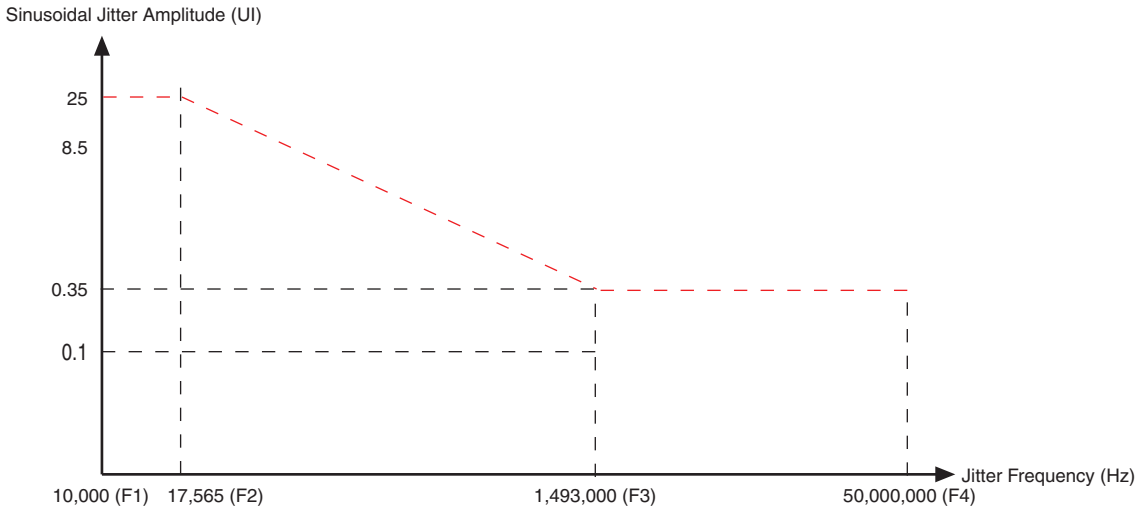


Table 1–56 lists the LVDS soft-CDR/DPA sinusoidal jitter tolerance specification for Arria II GZ devices at 1.25 Gbps data rate.

Table 1–56. LVDS Soft-CDR/DPA Sinusoidal Jitter Mask Values for Arria II GZ Devices at 1.25 Gbps Data Rate

Jitter Frequency (Hz)		Sinusoidal Jitter (UI)
F1	10,000	25.000
F2	17,565	25.000
F3	1,493,000	0.350
F4	50,000,000	0.350

External Memory Interface Specifications

For the maximum clock rate supported for Arria II GX and GZ device family, refer to the External Memory Interface Spec Estimator page on the Altera website.

Table 1–57 lists the external memory interface specifications for Arria II GX devices.

Table 1–57. External Memory Interface Specifications for Arria II GX Devices (Part 1 of 2)

Frequency Mode	Frequency Range (MHz)			Resolution (°)	DQS Delay Buffer Mode *(1)*	Number of Delay Chains
	C4	I3, C5, I5	C6			
0	90-140	90-130	90-110	22.5	Low	16
1	110-180	110-170	110-150	30	Low	12
2	140-220	140-210	140-180	36	Low	10
3	170-270	170-260	170-220	45	Low	8
4	220-340	220-310	220-270	30	High	12

Table 1–57. External Memory Interface Specifications for Arria II GX Devices (Part 2 of 2)

Frequency Mode	Frequency Range (MHz)			Resolution (°)	DQS Delay Buffer Mode *(1)*	Number of Delay Chains
	C4	I3, C5, I5	C6			
5	270-410	270-380	270-320	36	High	10
6	320-450	320-410	320-370	45	High	8

Note to Table 1–57:

(1) Low indicates a 6-bit DQS delay setting; high indicates a 5-bit DQS delay setting.

Table 1–58 lists the DLL frequency range specifications for Arria II GZ devices.

Table 1–58. DLL Frequency Range Specifications for Arria II GZ Devices

Frequency Mode	Frequency Range (MHz)		Available Phase Shift	DQS Delay Buffer Mode *(1)*	Number of Delay Chains
	–3	–4			
0	90-130	90-120	22.5°, 45°, 67.5°, 90°	Low	16
1	120-170	120-160	30°, 60°, 90°, 120°	Low	12
2	150-210	150-200	36°, 72°, 108°, 144°	Low	10
3	180-260	180-240	45°, 90°,135°, 180°	Low	8
4	240-320	240-290	30°, 60°, 90°, 120°	High	12
5	290-380	290-360	36°, 72°, 108°, 144°	High	10
6	360-450	360-450	45°, 90°, 135°, 180°	High	8
7	470-630	470-590	60°, 120°, 180°, 240°	High	6

Note to Table 1–58:

(1) Low indicates a 6-bit DQS delay setting; high indicates a 5-bit DQS delay setting.

Table 1–59 lists the DQS phase offset delay per stage for Arria II GX devices.

Table 1–59. DQS Phase Offset Delay Per Setting for Arria II GX Devices *(Note 1)*, *(2)*, *(3)*

Speed Grade	Min	Max	Unit
C4	7.0	13.0	ps
I3, C5, I5	7.0	15.0	ps
C6	8.5	18.0	ps

Notes to Table 1–59:

(1) The valid settings for phase offset are -64 to +63 for frequency modes 0 to 3 and -32 to +31 for frequency modes 4 to 5.

(2) The typical value equals the average of the minimum and maximum values.

(3) The delay settings are linear.

IOE Programmable Delay

Table 1–66 lists the delay associated with each supported IOE programmable delay chain for Arria II GX devices.

Table 1–66. IOE Programmable Delay for Arria II GX Devices

Parameter	Available Settings (1)	Minimum Offset (2)	Maximum Offset								Unit
			Fast Model			Slow Model					
			I3	C4	I5	I3	C4	C5	I5	C6	
Output enable pin delay	7	0	0.413	0.442	0.413	0.814	0.713	0.796	0.801	0.873	ns
Delay from output register to output pin	7	0	0.339	0.362	0.339	0.671	0.585	0.654	0.661	0.722	ns
Input delay from pin to internal cell	52	0	1.494	1.607	1.494	2.895	2.520	2.733	2.775	2.944	ns
Input delay from pin to input register	52	0	1.493	1.607	1.493	2.896	2.503	2.732	2.774	2.944	ns
DQS bus to input register delay	4	0	0.074	0.076	0.074	0.140	0.124	0.147	0.147	0.167	ns

Notes to Table 1–66:

(1) The available setting for every delay chain starts with zero and ends with the specified maximum number of settings.

(2) The minimum offset represented in the table does not include intrinsic delay.

Table 1–67 lists the IOE programmable delay settings for Arria II GZ devices.

Table 1–67. IOE Programmable Delay for Arria II GZ Devices

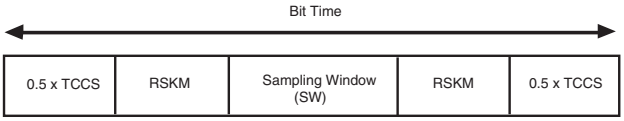
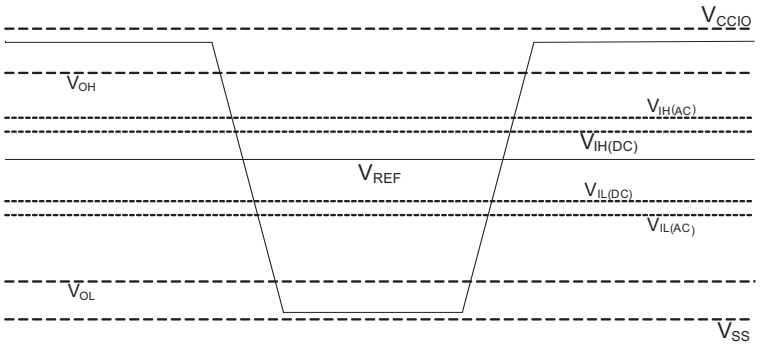
Parameter	Available Settings (1)	Minimum Offset (2)	Maximum Offset						Unit
			Fast Model		Slow Model				
			Industrial	Commercial	C3	I3	C4	I4	
D1	15	0	0.462	0.505	0.795	0.801	0.857	0.864	ns
D2	7	0	0.234	0.232	0.372	0.371	0.407	0.405	ns
D3	7	0	1.700	1.769	2.927	2.948	3.157	3.178	ns
D4	15	0	0.508	0.554	0.882	0.889	0.952	0.959	ns
D5	15	0	0.472	0.500	0.799	0.817	0.875	0.882	ns
D6	6	0	0.186	0.195	0.319	0.321	0.345	0.347	ns

Notes to Table 1–67:

(1) You can set this value in the Quartus II software by selecting **D1**, **D2**, **D3**, **D4**, **D5**, and **D6** in the **Assignment Name** column.

(2) Minimum offset does not include the intrinsic delay.

Table 1–68. Glossary (Part 3 of 4)

Letter	Subject	Definitions
S	**SW (sampling window)**	The period of time during which the data must be valid in order to capture it correctly. The setup and hold times determine the ideal strobe position within the sampling window: *Timing Diagram* 
	Single-ended Voltage Referenced I/O Standard	The JEDEC standard for SSTL and HSTL I/O standards define both the AC and DC input signal values. The AC values indicate the voltage levels at which the receiver must meet its timing specifications. The DC values indicate the voltage levels at which the final logic state of the receiver is unambiguously defined. After the receiver input has crossed the AC value, the receiver changes to the new logic state. The new logic state is then maintained as long as the input stays beyond the AC threshold. This approach is intended to provide predictable receiver timing in the presence of input waveform ringing: *Single-Ended Voltage Referenced I/O Standard* 
T	t_C	High-speed receiver and transmitter input and output clock period.
	TCCS (channel-to-channel-skew)	The timing difference between the fastest and slowest output edges, including t_{CO} variation and clock skew, across channels driven by the same PLL. The clock is included in the TCCS measurement (refer to the *Timing Diagram* figure under **S** in this table).
	t_{DUTY}	High-speed I/O block: Duty cycle on the high-speed transmitter output clock.
		Timing Unit Interval (TUI) The timing budget allowed for skew, propagation delays, and data sampling window. (TUI = 1/(Receiver Input Clock Frequency Multiplication Factor) = t_C/w)
	t_{FALL}	Signal high-to-low transition time (80-20%)
	t_{INCCJ}	Cycle-to-cycle jitter tolerance on the PLL clock input.
	t_{OUTPJ_IO}	Period jitter on the general purpose I/O driven by a PLL.
	t_{OUTPJ_DC}	Period jitter on the dedicated clock output driven by a PLL.
	t_{RISE}	Signal low-to-high transition time (20-80%).